Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/614,324	UEYAMA ET AL.
Examiner	Art Unit
Louise N. Learv	1655

	SEAR	CHED	:
Class	Subclass	Date	Examiner
4 <u>3</u> 5	7.1	11/11/2005	LL
435	4	11/11/2005	LL
	,		

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

DATE 11/11/2005 11/11/2005	LL LL
11/11/2005	LL
:	